

Tomography Acquisition -or-The First "R" (of 3)

Sharon Grayer Wolf



Tomography workflow



- 1. Sample preparation (Eyal, Katya)
- 2. Correlative Light-Electron
 - Microscopy -CLEM (Tali)
- 3. Data acquisition (Sharon)
- 4. Image processing (Nadav)



Data Acquisition



- 1. Microscope Components important for Tomography workflow (EVERYTHING)
 - a) Electron guns
 - b) Higher Voltage for thick specimens
 - c) Sample exchange system
 - d) Excellent vacuum systems
 - e) Stable optics
 - f) Energy filter
 - g) Phase plates
 - h) Cameras/detectors
- 2. Tomography Acquisition
 - a) Tilt schemes
 - b) Dose considerations
 - c) Defocus, magnification choices that affect resolution
 - d) Data collection software



Electron Sources





LaB6

FEG

Practical Electron Microscopy and Database: www.globalsino.com/EM/



Electron Sources



- Thermionic guns: Electron emission through heating.
- Field Emission Guns (FEG): Electron emission through applying an extraction voltage.

Properties	Tungsten	LaB6	FEG
Work function / eV	4.5	2.4	4.5
Temperature / K	2700	2000	1800
Energy spread / eV	3-4	1.5-3	0.4-1.5
Source size / nm	30000	5000	3-20
Maximum current / nA	1000	500	300
Brightness / A/m ² sr	10 ⁹	5x10 ¹⁰	1013
Lifetime / h	100	500	> 1000



Increasing voltage increases mean free path



Elastic scattering

Screened relativistic Rutherford cross section

Can be plotted as an equivalent mean free path vs. incident energy

This gives you a good sense on allowable sample thickness!



https://nanohub.org/resources/4003/watch?resid=27358







CryoTEM relies on Phase Contrast which

requires:

COHERENT, ELASTIC SCATTERING

Russo, C.J. and L.A. Passmore, Curr Op Struct Biol, 2016. 37: p. 81-89.



CryoTEM: Sample thickness is limited by the INELASTIC MEAN FREE PATH





- Elastic scattering
- Inelastic scattering

Cross-section: elastic ~ $Z^{3/2}$ inelastic ~ $Z^{1/2}$

Ratio inelastic/elastic ~ 20/Z

Inelastic mean free path in vitrified water for 200kV $\sim 250 \ nm$

The "Natural" limit for cryoTEM Tomography

For thick samples, few "useful" (elastic) electrons remain: () TO CELLS



EELS SPECTRA



Energy Filter





https://www.globalsino.com/EM/page4780.html



Energy Filter









Why Phase Plates? Enhanced Contrast





Danev R and Baumeister W, Curr Opin Struct Biol 46, 87-94 (2017)



Why Phase Plates? Enhanced Contrast





Fukuda Y et al, J. Struct Biol **190(2)**, 143-154 (2015)



Cryo-Specimen holders - side entry













Cryo-Specimen holders – cartridge systems











Charge-Coupled Device (CCD) cameras



Electrons are converted into photons of light before being detected.



Courtesy of Hans Tietz, TVIPS

CMOS (complementary metal-oxide semiconductor) cameras





CCDs move photogenerated charge from pixel to pixel and convert it to voltage at an output node. CMOS imagers convert charge to voltage inside each pixel.

http://meroli.web.cern.ch/meroli/lecture_cmos_vs_ccd_pixel_sensor.html



Why Direct Electron Detection?



CCD Camera

- Signal from one electron spreads in the scintillator and is recorded in several pixels
- At higher voltages, 20-30% of electrons scatter back into phosphor in the wrong place
 - Spurious signals ruin resolution and efficiency

Direct Detector

- Signal from one electron is generated mostly within one pixel
- Backscatter is much less if the substrate is thin enough





David Mastronarde, 2019 Vienna Course on Tomography



Why Direct Electron Detection?







IMAGING LIFE FROM MOLECULES TO CELLS

IMpaCT

Indirect (left) and Direct (right) detection and Monte Carlo simulations of electron tracks within the device

From Gatan Inc. website



Electron Counting



- Single electron events can be distinguished if frames are read out fast enough and number of electrons in each is low enough
- Electron counting helps by about a factor of 2 because it:
 - Reduces blurring from signals spreading to more than one pixel
 - Eliminates effects of variable sized packets of signal and of readout noise, which impair the signal-to-noise ratio



Single electron events in one frame from an active pixel sensor McMullan et al., 2009, Ultramicroscopy 109: 1411–1416

David Mastronarde, 2019 Vienna Course on Tomography



Why Direct Electron Detection?

Single electron counting brings noise down to practically zero



Standard Integrated Mode

1. Electron enters detector



2. Signal Is Scattered



3. Charge collects in each pixel



Single Electron Counting Mode

4a. Events are reduced to the highest charge pixels



From Gatan Inc. website

4b. Events are localized with sub-pixel accuracy





Direct Electron Detector (DED) cameras



Figure 1. Electron micrograph of double-layered rotavirus particles frozen in a thin layer of amorphous ice. The image was recorded by the author and co-workers using the DE-12 direct electron detector (Direct Electron, San Diego, United States) in movie mode at 40 frames per second. In panel A, 60 frames have been averaged without alignment, resulting in an image that is blurred due to beam-inducted movement. In panel B the frames have been aligned to compensate for this movement, which results in an image with significantly reduced blurring and improved contrast. The alignment method used here involved tracking the movement of the particles (Brilot et al., 2012); the alignment method used by Bai et al. used additional statistics to predict the movement of the particles caused by the electron beam. Scale bar = 50 nm.





Image formation in STEM – incoherent detection, particle nature







CryoTEM: Sample thickness is limited by the INELASTIC MEAN FREE PATH





- Elastic scattering
- Inelastic scattering

Cross-section: elastic ~ $Z^{3/2}$ inelastic ~ $Z^{1/2}$

Ratio inelastic/elastic ~ 20/Z

Inelastic mean free path in vitrified water for 200 kV $\sim 250 \ nm$

The "Natural" limit for cryoTEM Tomography



CryoSTEM: Sample thickness is limited by the ELASTIC MEAN FREE PATH





- Elastic scattering
- Inelastic scattering

Cross-section: elastic ~ $Z^{3/2}$ inelastic ~ $Z^{1/2}$

Ratio inelastic/elastic ~ 20/Z

Elastic mean free path in vitrified water for 200 kV ~ 750 nm

The "Natural" limit for cryoSTEM Tomography

CryoSTEM: Efficient use of electrons





CryoSTEM relies on *Amplitude Contrast which*

requires:

INELASTIC or ELASTIC SCATTERING (but only one elastic scattering event)

Russo, C.J. and L.A. Passmore, Curr Op Struct Biol, 2016. 37: p. 81-89.



STEM Detectors





Andre Wisnet, 2019 Vienna Course on Tomography



STEM Phase-contrast Detectors

 $E = -\nabla V$

DPC = Vil



4-quadrant and annular rings (F20)



"integrated **D**ifferential **P**hase Contrast (iDPC) Yücelen et al, Sci Rep 2017

h)

4 quadrant (Krios)

Focused Electron Probe

Sample

Annular DF Detector

egmented Detector

Figure 1. Schematic representation of the experimental setup. (a) Focused probe without sample. (b) Focused

probe with a sample.

Under development Michael Elbaum, Lothar Houben, El Mul company



Simultaneous BF and DF data collection. Dynamic Focus Agrobacteria

bright field



dark field



Wolf, Houben & Elbaum, Nature Methods 2014

Human WI-38 fibroblasts, ECM, 750 nm thick

Deborah Fass, Michael Elbaum

CSTET BF tilt series



CSTET BF reconstruction, 30 nm thick slices



 $-65^{\circ} \rightarrow +70^{\circ}$, every 2°, every 1.5° above 50°

Wolf et al, eLIFE. 6:e29929.













Dense parts of granules

Densest regions of ribosomes All ribosomal volumes

Wolf et al, eLIFE. 6:e29929.



EDX shows Ca, P





Wolf et al, eLIFE. 6:e29929.



Microscopes – which one to use?





Tecnai T12

Good:

- LaB6 source
- Decent vacuum system
- Very sensitive CMOS camera (TVIPS)
- Cryo-blades

Bad:

- LaB6 source
- Only 100 kV

Tecnai T12

In practice:

Used for screening and high quality TEM imaging of cryosamples, negative stain samples, general biological TEM

Tecnai F20

Good:

- FEG source
- Decent vacuum system
- Direct Electron Detector for TEM
- Easy Switching from TEM to STEM
- Multiple STEM detectors
- Stable optics
- 200 kV
- Energy filter for tomography

Bad:

- Side entry holder
- Cryoblades and vacuum system not adequate enough for long-term cryo-sessions
- No convenient automated liquid N2 filling system
- Complicated interfaces with multiple computers
- Communication issues

Tecnai F20

In practice:

Not usually used for data collection for cryo-samples.

Used for data collection for plastic sections, TEM and STEM.

Talos Arctica

- FEG
- Stable Optics
- 2-condenser lens system
- 200 kV
- Gatan CMOS camera (Oneview)
- STEM imaging

Adjacent operator room

Titan Krios

- FEG
- Super Stable Optics power lenses
- 3-condenser lens system
- 300 kV
- Two DED's (Falcon III and GIF/K3)
- Energy Filter (with K3)
- STEM imaging

Data Collection - Considerations

What total dose? Resolution vs signal-to-noise

What tilt range? Completeness of information vs dose and speed

What angular increment? Resolution vs dose and speed

What order to collect the images? Speed, reliability, optimal dose, sample distortion...

What magnification? Resolution and DQE vs field of view

What defocus? High-frequency information vs low frequency information

John Briggs Lecture, MRC Cryo-EM course 2017 https://www2.mrc-lmb.cam.ac.uk/research/scientific-training/electron-microscopy/

What Magnification?

The Shannon Theorem

If a function x(t) contains no frequencies higher than $B \frac{\text{hertz}}{\text{hertz}}$, it is completely determined by giving its ordinates at a series of points spaced 1/(2B) seconds apart.

The Nyquist Limit

f(s) is the sampling rate

Example of undersampling:

Two different sine waves can accurately describe the sampled data. So data is not adequately sampled for this frequency.

How much do we have to sample to get a desired resolution?

FIGURE 1. (a) An asymmetric particle of maximum diameter D containing features on a scale d. (b) Two-dimensional illustration of the 'filling-up' of Fourier space by central sections. Data must be collected to a radius of 1/d if the reconstruction is to show detail to a resolution d. The angular separation is decided as follows. The Fourier transform of a particle of diameter D does not, on the average, change appreciably over a distance 1/D in a Fourier space. There will thus be a sufficient number of sections if their intersections with a circle of radius 1/d are spaced at intervals at least as small as 1/D. The minimum number of views, n, is therefore equal to $n = \pi(1/D)/(1/d) = \pi D/d$. For a particle of diameter 20 nm, to be solved to a resolution of 2 nm, $n \approx 30$. The value of n will in practice need to be greater since the calculation assumes that all the data can be collected by a set of tilts about a single axis covering a range of $\pm 90^{\circ}$. This is impossible in practice. Limited ranges of tilts about more than one axis will have to be employed, and the strategy of data collection can be worked out by the methods given by Crowther, DeRosier & Klug (1970).

Optical Diffraction and Filtering and Three-Dimensional Reconstructions from Electron Micrographs Author(s): A. Klug Source: *Philosophical Transactions of the Royal Society of London. Series B, Biological Sciences*, Vol. 261, No. 837, A Discussion on New Developments in Electron Microscopy with Special Emphasis on their Application in Biology, (May 27, 1971), pp. 173-179

John Briggs Lecture, MRC Cryo-EM course 2017 https://www2.mrc-lmb.cam.ac.uk/research/scientific-training/electron-microscopy/

Crowther Criterion

 $r = \pi D/N$

r: Resolution limit N: Number of projections D: Object thickness

Tilt Schemes

Hagen WJH, Wan W and Briggs JAG, J. Struct Biol. 197(2), 191-198 (2017)

Tilt Schemes – signal transfer

Hagen WJH, Wan W and Briggs JAG, J. Struct Biol. 197(2), 191-198 (2017)

Data Collection - Considerations

	Strategy to increase contrast	Strategy to increase resolution	Strategy to deal with thick samples		Strategy to increase contrast	Strategy to increase resolution	Strategy to deal with thick samples
Voltage	Low	High	High	Tilt	Large	Small	Large
	(200 keV) as	(300 keV)	(300 keV)	increment	(more e- per	(sample fine	(facilitates
	thickness				image)	details but not important for	higher SNR,
	allows					subtomogram averaging)	enabling
Total electron	High (>100e-/A2)	Low (<50e-/A2)	High (>100e-/A2)				alignment
dose							of tilt series)
Defocus	High (–5um	Low (–2um	High (–5um	Tilt scheme	Not relevant	Dose symmetric	Dose symmetric
	to –15um)	to –4um)	to –15um)	Phase plates	Always use	Alw vz zse	Always use
Magnification	Low (more e-	High (pixel	Low (more e-		if possible	if y ss. e	if possible
	per pixel)	size half	per pixel)	Energy filter	Always use	Always use	Always use
		Nyquist)			if possible	if possible	if possible
Tilt range	Low	Higher	Low				
	(maximise e-	(decrease	(extreme tilts	Imaging mode: STEM		TEM	STEM
	dose per	missing	will be even				STEIM
	projection	wedge)	thicker)				

image)

Adapted from: Ferreira J.L., Matthews-Palmer T.R.S., Beeby M. (2018) Electron Cryo-Tomography. In: Hanssen E. (eds) Cellular Imaging. Biological and Medical Physics, Biomedical Engineering. Springer, Cham.

TFS Tomography Interface - ATLAS

TFS Tomography Interface Presets – Search/Template

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TFS Tomography Interface Presets – Exposure

TFS Tomography Interface Presets – Exposure

IMPACT IMAGING LIFE FROM MOLECULES TO CELLS

TFS Tomography Interface Autofxns – Eucentric height MpaCT

IMAGING LIFE FROM MOLECULES TO CELLS

TFS Tomography Interface Autofxns – Eucentric height

IMAGING LIFE FROM MOLECULES TO CELLS

TFS Tomography Interface Autofxns – focusing

TFS Tomography Interface STEM dynamic focusing

TFS Tomography Interface STEM dynamic focusing

TFS Tomography Interface - Set up Tomography

Preparation (STEN) Atlas	STEN Tomography Auto Functions Tomography Calibrations Tomography Visualizer	
Specimen		and the second second second second
Tooka &	Experiment settings	Messeger
Seasion Schip	Name supervisor 20201719 141024	Adjusting STEM rotation to -90.68*
TR. Series	Specimen Upo Slab-like @Rsd-like	Adjusting STEM rotation to -90.68*
	Description	
	C Low Dose	Status
	C Banch	
	Image file format MRC 2014	
	Output tolder EVunk	
A Callen Mar		
	Fecipients	
	Test	
	Send email on completion or termination of automated acquisition	
	Apply	

TFS Tomography Interface - Prepare Position

TFS Tomography Interface - Prepare Position

TFS Tomography Interface - Refine Positions

TFS Tomography Interface - Refine Positions

TFS Tomography Interface - Refine Positions

TFS Tomography Interface - Tilt Series Parameters

Tilt Series Acquisition		Tilt Scheme		Focus	
Start Angle [°]	-30.00	오 Linear 🛛 🔘	Saxton	Use Dynamic Focus	
Max. Negative Angle [°]	-65.00	Low Tilt Step [°]	2.00	Defocus (at 0°) [µm] 0.000	
Max. Positive Angle [°]	65.00	High Tilt Switch [°]	80.00	Detectors	
Stage Relaxation Time [s]	3.00	High Tilt Step [°]	1.00	Use Additional Detectors	
Partial tilt series				🗹 BF 🥅 DF2 🥅 DF4	
				V HAADF	
L)	L	J	L	
Acquisition Output					
Output File Name	Dummy				
Apply Reset					

TFS Tomography Interface - Tilt Series Corrections

TFS Tomography Interface - Acquisition

References – emphasis on cellular tomography

> Chapter 10, Biomedical Electron Microscopy, "Microscopy", Maunsbach and Afzelius

https://doi.org/10.1016/B978-012480610-8/50012-3 (1999)

Old book with great images demonstrating various optical phenomena, using biological sections as examples.

- Transmission Electron Microscopy (textbook), DB Williams & CB Carter (2009)
 Excellent general chapters for electron optics.
- Cellular Imaging: Electron Tomography and Related Techniques, Ed. E Hanssen, Springer (2018).
 Recent book covering the field.
- Methods in Cell Biology, Volume 152: Three-Dimensional Electron Microscopy, Ed. T Muller-Reichert & G Pigino (2019).

Another recent book including practical guidelines in many chapters.

Electron Tomography Methods for Three-Dimensional Visualization of Structures in the Cell, 2nd
 Edition, Ed. J Frank, Springer (2006).

The basic tomography principles